


<b>Search Notes</b>  	<b>Application/Control No.</b>  10759719	<b>Applicant(s)/Patent Under Reexamination</b>  LEE ET AL.
	<b>Examiner</b>  SHIN-HON CHEN	<b>Art Unit</b>  2131

### SEARCHED

Class	Subclass	Date	Examiner
380	256	3/28/08	S.C.
380	30, 259, 282	7/18/08	S.C.
726	2, 3	7/18/08	S.C.

### SEARCH NOTES

Search Notes	Date	Examiner
USPAT, PGPUB, DERWENT, JPO, EPO (BRS search - see search history)	3/28/08	S.C.
NPL search (IEEE explor and Google)	3/27/08	S.C.
USPAT, PGPUB, DERWENT, JPO, EPO (BRS search - updated search)	7/18/08	S.C.

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
380	256, 259, 282, 30	7/18/08	S.C.
726	2, 3	7/18/08	S.C.